

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SJ/T 11820-2022

**Technical requirements and measurement methods for DC
parameter test equipment of semiconductor discrete devices**

半导体分立器件直流参数测试设备技术要求和测量方法

(English Translation)

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This standard specifies the terms and definitions, technical requirements, and measurement methods of DC parameter test equipment for semiconductor discrete devices. It is suitable for discrete device testing equipment with DC voltage output and DC voltage measurement range not exceeding 0.01V~5000V, DC current output and DC current measurement range not exceeding 1nA~10A, pulse current output and pulse current measurement range not exceeding 10A~1200A.

Document data

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